



SCOPE OF ACCREDITATION TO ISO/IEC 17025:2005

CERTIFIED MEASUREMENTS, INC.
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CALIBRATION

Valid To: May 31, 2018

Certificate Number: 1297.01

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following calibrations and dimensional inspections¹:

I. Dimensional

Parameter/Equipment	Range	CMC ^{2,4} (±)	Comments
Gage Blocks	Up to 1 in (1 to 4) in (4 to 20) in	(2.4 + 0.78L) µin (3.0 + 0.78L) µin (6.0 + 0.78L) µin	Mechanical comparison
Measuring Wires	(2 to 120) TPI	8.0 µin	Standard measuring machine
Plain Rings	(0.125 to 0.25) in (0.25 to 11) in (11 to 16) in	(30 + 1.6L) µin (20 + 1.6L) µin (27 + 1.6L) µin	Master ring and standard measuring machine
Plain Plugs	(0.125 to 16) in	(8.0 + 1.6L) µin	Master plug and standard measuring machine
Threaded Plugs/Rings –			
Plug Pitch Diameter	(0.1 to 10) in	(54 + 2.2D) µin	Gage blocks, standard measuring machine, master thread wires
Plug Major Diameter	(0.1 to 10) in	22 µin	Gage blocks and standard measuring machine.
Ring Major Diameter	(0.06 to 2) in	190 µin	Master setting plugs

Parameter/Equipment	Range	CMC ^{2,4} (±)	Comments
Length Standards	Up to 12 in (12 to 49) in	(19 + 2.9L) μin (60 + 3.6L) μin	Gage blocks and standard measuring machine
Dial Indicators ³	Up to 1 in (1 to 4) in	30 μin 250 μin	Indicator calibrator
Micrometers ³ – Digital Vernier	Up to 6 in (1 to 36) in	34 μin (62 + 2.5L) μin	Gage blocks
Tape Measures	(6 to 100) ft	(0.002 + 0.00004L) in	CMM/master rule
Glass Scales	(3 to 16) in (> 16 to 20) in Up to 3 in	(40 + 1.5L) μin (60 + 11L) μin 35 μin	Standard measuring machine and microscope
Height Measures	(6 to 24) in (> 24 to 48) in	95 μin 400 μin	Gage amp/probe and gage blocks
Angle Blocks	Up to 45°	2.0”	Sine bar, gage blocks and gage amp/probe
Protractors, Levels and Clinometers	Up to 359°	6.0”	Rotary tilting table
Calipers ³	Up to 12 in (12 to 60) in	380 μin (620 + 18L) μin	Gage blocks and ring gages
Indicating Comparators	0.002 in	11 μin	UMM, American SIP 550M
Steel Rules	Up to 72 in	(0.001 + 0.00003L) in	Manual CMM

Parameter/Equipment	Range	CMC ² (±)	Comments
Optical Flats and Parallels –			
Flatness	Up to 4 in	3.0 μin	Master flat
Parallelism	Up to 100 μin	2.0 μin	Gage block comparator

II. Dimensional Testing/Calibration¹

Parameter/Equipment	Range	CMC ² (±)	Comments
Length – 3D ⁶	X: (0 to 20) in Y: (0 to 16) in Z: (0 to 12) in	170 μin	CMM
Length – 2D ⁶	X: Up to 6 in Y: Up to 2 in	170 μin	Optical comparator
Angle ⁶	Up to 360°	0.038°	Optical comparator

III. Electrical – DC/Low Frequency

Parameter/Range	Frequency	CMC ^{2,5} (±)	Comments
AC Current – Measure and Generate			
(0.001 to 2) A	40 Hz to 20 kHz	0.01 %	AC current shunts Fluke A40, Fluke 792A and Agilent 3458A
(> 2 to 20) A		0.04 %	

Parameter/Range	Frequency	CMC ^{2,5} (±)	Comments
AC Voltage – Measure and Generate			
22 mV (10, 20) mV	10 Hz 20 Hz to 20 kHz 50 kHz	0.038 % 0.033 % 0.036 %	AC/DC transfer standard 792A with Datron 1271 DMM and Datron 4808 calibrator
220 mV (20 mV)	10 Hz 20 Hz 40 Hz to 20 kHz 50 kHz	0.042 % 0.028 % 0.024 % 0.027 %	
(60 mV)	10 Hz 20 Hz 40 Hz to 20 kHz 50 kHz	0.025 % 0.015 % 0.010 % 0.013 %	
(100, 200) mV	10 Hz 20 Hz 40 Hz to 20 kHz (50 to 100) kHz (300 to 500) kHz 800 kHz to 1 MHz	0.025 % 0.012 % 0.010 % 0.019 % 0.072 % 0.072 %	
700 mV (200, 600) mV	10 Hz 20 Hz 40 Hz to 20 kHz (50 to 100) kHz 300 kHz to 1 MHz	0.026 % 0.010 % 0.008 % 0.019 % 0.072 %	
2.2 V (0.6, 1, 2) V	10 Hz 20 Hz 40 Hz to 20 kHz (50 to 100) kHz 300 kHz to 1 MHz	0.025 % 0.010 % 0.065 % 0.008 % 0.064 %	
7 V (2, 6) V	10 Hz 20 Hz 40 Hz to 20 kHz (50 to 100) kHz 300 kHz to 1 MHz	0.025 % 0.010 % 0.006 % 0.009 % 0.055 %	

Parameter/Range	Frequency	CMC ^{2,5} (±)	Comments		
AC Voltage – Measure and Generate (cont)					
22 V (6, 10) V	10 Hz 20 Hz 40 Hz to 20 kHz (50 to 100) kHz 300 kHz to 1 MHz	0.025 % 0.010 % 0.007 % 0.010 % 0.056 %	AC/DC transfer standard 792A with Datron 1271 DMM and Datron 4808 calibrator		
(20 V)	10 Hz 20 Hz 40 Hz to 50 kHz	0.025 % 0.010 % 0.070 %			
70 V (20, 60) V	10 Hz 20 Hz 40 Hz to 20 kHz 50 kHz	0.025 % 0.010 % 0.007 % 0.010 %			
220 V (60, 100, 200) V	10 Hz 20 Hz 40 Hz to 20 kHz 50 kHz	0.025 % 0.012 % 0.008 % 0.010 %			
1000 V (200, 600, 1000) V	10 Hz 20 Hz 40 Hz to 20 kHz	0.025 % 0.012 % 0.008 %			
(200, 600, 700) V	50 kHz	0.01 %		Reference thermal converter	
(1 to 3) V	(1 to 13) MHz (13 to 30) MHz (30 to 80) MHz (80 to 100) MHz	0.14 % 0.29 % 0.58 % 1.40 %			
(1 to 10) kV	(30 to 200) Hz	0.30 %			Vitretek 4700
Measure Only (> 10 to 50) kV	(30 to 100) Hz	0.40 %			Vitretek 4700 w/ HVL-70

Parameter/Equipment	Range	CMC ^{2,5} (±)	Comments
DC Current – Measure and Generate	0.1 µA to 2 A	55 µA/A	Datron 4808, Datron 1271
	(2 to 20) A	0.03 %	Precision shunts, L&N 4300 and Guildline 9711A
	(20 to 100) A	0.07 %	Valhalla 2555A
DC Voltage – Measure and Generate	100 µV to 100 mV	8 µV/V + 0.4 µV	Kelvin-Varley divider Fluke 720A Fluke 720A/Fluke 732A Fluke 732A Fluke 752A divider, Fluke 732A and Datron 4808 Fluke 80E-10
	100 mV to 1 V	3.4 µV/V + 0.4 µV	
	(1 to 10) V	3.0 µV/V + 3.0 µV	
	10 V	1.0 µV/V	
Measure Only	(10 to 100) V	5.0 µV/V + 50 µV	Vitrek 4700 w/ HVL-70 Vitrek 4700 w/ HVL-70
	(100 to 1000) V	3.9 µV/V + 500 µV	
	(1 to 10) kV	0.02 %	
Resistance – Measure and Generate, Fixed Values	(10 to 20) kV	0.07 %	Measurement Intl 9331 series reference standard resistors with Agilent 3458A
	(20 to 50) kV	0.20 %	
	0.001 Ω	0.01 %	
	0.01 Ω	0.01 %	
	0.1 Ω	10 µΩ/Ω	
	1 Ω	7.4 µΩ/Ω	
	10 Ω	7.0 µΩ/Ω	
	100 Ω	7.3 µΩ/Ω	
	1 kΩ	7.2 µΩ/Ω	
	10 kΩ	7.0 µΩ/Ω	
100 kΩ	7.3 µΩ/Ω		
1 MΩ	10 µΩ/Ω		
10 MΩ	12 µΩ/Ω		
100 MΩ	32 µΩ/Ω		
Resistance – Measure and Generate, Fixed Values	1 GΩ	0.058 %	Guildline 9520/6500A
	10 GΩ	0.08 %	
	100 GΩ	0.12 %	
	1 TΩ	0.23 %	
Capacitance – Measure and Generate			
50 Hz to 1 kHz	(1 to 100) µF	0.1 %	GenRad 1689 capacitance bridge
	100 µF to 1 mF	0.15 %	
Capacitance – Measure and Generate @ 1 kHz	11 aF to 1.1 µF	0.017 % + 0.00003 pF	GenRad 1615 capacitance bridge and GenRad 1404-A standard capacitor

Parameter/Range	Frequency	CMC ^{2,5} (±)	Comments
Inductance – Generate			
100 µH to 10 mH (10 to 100) mH 100 mH to 1 H (1 to 10) H	1 kHz 500 Hz 200 Hz 100 Hz	2.0 % 1.6 % 0.8 % 0.8 %	GenRad 1491G decade inductor
Fixed Point 200 mH	100 Hz, 200 Hz, 400 Hz, 1 kHz, & 10 kHz	0.15 %	GenRad 1482M std inductor
Inductance ³ – Measure			
100 µH to 10 H	100 Hz, 200 Hz, 400 Hz, 1 kHz, & 10 kHz	0.20 %	GenRad 1689 RLC Digibridge

Parameter/Equipment	Range	CMC ² (±)	Comments
Electrical Simulation of Thermocouple Indicators –			
Type E	(-250 to -100) °C (-100 to -25) °C (-25 to 350) °C (350 to 650) °C (650 to 1000) °C	0.12 °C 0.16 °C 0.14 °C 0.16 °C 0.21 °C	Fluke 5500A/ ice reference
Type J	(-210 to -100) °C (-100 to -30) °C (-30 to 150) °C (150 to 760) °C (760 to 1200) °C	0.27 °C 0.16 °C 0.14 °C 0.17 °C 0.23 °C	
Type K	(-200 to 100) °C (-100 to -25) °C (-25 to 120) °C (120 to 1000) °C (1000 to 1372) °C	0.33 °C 0.18 °C 0.16 °C 0.26 °C 0.4 °C	
Type N	(-200 to -100) °C (-100 to -25) °C (-25 to 120) °C (120 to 410) °C (410 to 1300) °C	0.4 °C 0.22 °C 0.19 °C 0.18 °C 0.27 °C	

Parameter/Equipment	Range	CMC ² (±)	Comments
Electrical Simulation of Thermocouple Indicators – (cont)			
Type R	(0 to 250) °C (250 to 400) °C (400 to 1000) °C (1000 to 1767) °C	0.57 °C 0.35 °C 0.33 °C 0.40 °C	Fluke 5500A/ ice reference
Type S	(0 to 250) °C (250 to 1000) °C (1000 to 1400) °C (1400 to 1767) °C	0.47 °C 0.36 °C 0.37 °C 0.46 °C	
Type T	(-250 to -150) °C (-150 to 0) °C (0 to 120) °C (120 to 400) °C	0.63 °C 0.24 °C 0.16 °C 0.14 °C	
Electrical Simulation of Thermocouple Indicators ³ –			
Type E	(-250 to -100) °C (-100 to -25) °C (-25 to 350) °C (350 to 650) °C (650 to 1000) °C	0.58 °C 0.19 °C 0.16 °C 0.19 °C 0.24 °C	Fluke 5500A or Fluke 742x process calibrator
Type J	(-210 to -100) °C (-100 to -30) °C (-30 to 150) °C (150 to 760) °C (760 to 1200) °C	0.31 °C 0.19 °C 0.16 °C 0.20 °C 0.27 °C	
Type K	(-200 to 100) °C (-100 to -25) °C (-25 to 120) °C (120 to 1000) °C (1000 to 1372) °C	0.38 °C 0.21 °C 0.19 °C 0.30 °C 0.46 °C	
Type T	(-250 to -150) °C (-150 to 0) °C (0 to 120) °C (120 to 400) °C	0.73 °C 0.28 °C 0.19 °C 0.16 °C	

Parameter/Equipment	Range	CMC ² (±)	Comments
Electrical Simulation of RTD Indicating Systems and Measure ³ –			
Pt 385, 100 Ω	(-200 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C (630 to 800) °C	0.05 °C 0.07 °C 0.09 °C 0.10 °C 0.12 °C 0.23 °C	Decade resistors and Datron 1271, Wavetek 1281, Fluke 741B
Pt 3926, 100 Ω	(-200 to 0) °C (0 to 100) °C (100 to 300) °C (300 to 400) °C (400 to 630) °C	0.05 °C 0.07 °C 0.09 °C 0.10 °C 0.12 °C	
Pt 3916, 100 Ω	(-200 to -190) °C (-190 to -80) °C (-80 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.25 °C 0.04 °C 0.05 °C 0.06 °C 0.07 °C 0.08 °C 0.09 °C 0.10 °C 0.23 °C	
Pt 385, 200 Ω	(-200 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 400) °C (400 to 600) °C (600 to 630) °C	0.04 °C 0.05 °C 0.12 °C 0.13 °C 0.14 °C 0.16 °C	
Pt 385, 500 Ω	(-200 to -80) °C (-80 to 100) °C (100 to 260) °C (260 to 400) °C (400 to 600) °C (600 to 630) °C	0.04 °C 0.05 °C 0.06 °C 0.08 °C 0.09 °C 0.11 °C	
Pt 385, 1000 Ω	(-200 to 0) °C (0 to 100) °C (100 to 260) °C (260 to 300) °C (300 to 600) °C (600 to 630) °C	0.03 °C 0.04 °C 0.05 °C 0.06 °C 0.07 °C 0.23 °C	
Ni 120, 120 Ω	(-80 to 100) °C (100 to 260) °C	0.08 °C 0.14 °C	
Cu 427, 10 Ω	(-100 to 260) °C	0.30 °C	

Parameter/Equipment	Range	CMC ^{2,5} (±)	Comments
Oscilloscopes ³ –			
Squarewave Signal – 50 Ω @ 1 kHz	1 mV to 6.6 V _{p-p}	0.25 % + 40 μV	Fluke 5500A/SC600
1 MΩ @ 1 kHz	1 mV to 130 V _{p-p}	0.1 % + 40 μV	
Leveled Sine Wave –	50 kHz reference	2.0 % + 300 μV	
Amplitude (50 kHz ref)	50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz	3.5 % + 300 μV 4.0 % + 300 μV 6.0 % + 300 μV	
Flatness (50 kHz ref)	50 kHz to 100 MHz (100 to 300) MHz (300 to 600) MHz	1.5 % + 100 μV 2.0 % + 100 μV 4.0 % + 100 μV	
Time Marker – Measuring Equipment and Period @ 50Ω	5 s to 50 ms 20 ms to 2 ns	0.12 % 2.5 μs/s	
Rise Time	≤ 1 ns	+0 / -500 ps	

IV. Electrical – Microwave/RF

Parameter/Range	Frequency	CMC ^{2,5} (±)	Comments
RF Power – (1 to 10) mW	(10 to 20) MHz (20 to 50) MHz 50 MHz to 8 GHz (8 to 18) GHz	1.6 % 1.5 % 1.4 % 1.5 %	Tegam F1109 coaxial power standard and Agilent E4418B power meter
RF Attenuation – (0 to -10) dB -20 dB -30 dB -40 dB -50 dB -60 dB -70 dB -80 dB -90 dB -100 dB	10 MHz to 18 GHz	0.065 dB 0.076 dB 0.092 dB 0.12 dB 0.14 dB 0.16 dB 0.18 dB 0.20 dB 0.47 dB 0.58 dB	Weinschel VM-4B attenuation calibrator

V. Fluid Quantities

Parameter/Equipment	Range	CMC ² (±)	Comments
Hydrometers	(0.7 to 2.0) g/cm ³ (sg)	0.00040 g/cm ³ (sg)	Verification of hydrometers in accordance with ASTM E126 by hydrostatic weighing using Westphall balance
Volumetric Ware – (To Contain or Deliver)	(1.0 to 10) mL (> 10 to 25) mL (> 25 to 50) mL (> 50 to 100) mL (> 10 to 200) mL (> 200 to 250) mL (> 250 to 500) mL (> 500 to 1000) mL	0.0054 mL 0.0063 mL 0.0085 mL 0.016 mL 0.026 mL 0.032 mL 0.064 mL 0.13 mL	NISTIR 7383 SOP #14 by gravimetric determination
Pipettes	10 µL (> 10 to 20) µL (> 20 to 50) µL (> 20 to 100) µL (> 100 to 200) µL (> 200 to 500) µL (> 500 to 1000) µL (> 1000 to 5000) µL	0.19 µL 0.27 µL 0.35 µL 0.48 µL 0.74 µL 1.5 µL 2.8 µL 4.8 µL	NISTIR 7383 SOP #14 by gravimetric determination

VI. Mechanical

Parameter/Equipment	Range	CMC ^{2,5} (±)	Comments
Torque – Wrenches ³ , Screwdrivers	(0.4 to 1000) ft·lbf	0.47 %	Torque transducers indicator
Watches	(0.6 to 100) in·ozf	0.33 %	Torque arms with ASTM Class 4 dead weight
Torque Analyzers, Transducers	(1 to 100) in·ozf (5 to 50) in·lbf (50 to 1200) in·lbf (100 to 600) ft·lbf (600 to 1000) ft·lbf	0.053 % 0.049 % 0.046 % 0.049 % 0.068 %	Torque arms with ASTM Class 4 dead weight

Parameter/Equipment	Range	CMC ^{2,5} (±)	Comments
Force – Tension and Compression	(5 to 1800) lbf	0.029 %	NIST Class F dead weights
	(500 to 5000) lbf (5000 to 50 000) lbf	0.065 % 0.072 %	Load cell comparison
Direct Verification of Durometers –			ASTM D2240 with
Scale Accuracy			
Type A, B, C, D, DO, E, M, O, OOO, OOO-S, R Type OO	(0 to 100) duros	0.30 duro points	Balance
	(0 to 100) duros	0.62 duro points	
Indenter Geometry –			
Length	Up to 0.2 in	0.00010 in	Gage blocks and optical comparator
Diameter	Up to 0.5 in	0.00020 in	
Angle	(30 to 35)°	0.038°	
Radius	Up to 0.25 in	0.00020 in	
Indenter Display	(0 to 100) duro units	0.30 duro units	Gage blocks
Spring Calibration – Force	(0 to 10) N (>10 to 50) N	0.0004 N 0.011 N	Balance
Cable Tensiometers/ Wire Tension Meters	(5 to 1000) lbf	0.74 %	NIST Class F dead weights
Pressure – Measure – Water Medium	(0.2 to 4) inH ₂ O	0.01 %	Micrometer standard barometer
Pressure – Measuring Equipment			
Gas Medium	(0.2 to 25) psi (25 to 100) psi (100 to 1000) psi	17 x 10 ⁻⁶ psi 19 x 10 ⁻⁶ psi 21 x 10 ⁻⁶ psi	Dead weight tester
Oil Medium	(1000 to 20 000) psi	49 x 10 ⁻⁶ psi	
Vacuum – Air/Gas Medium	(0.04 to 0.40) inHg	0.06 %	Absolute pressure gage
	(0.5 to 30) inHg	19 x 10 ⁻⁶ inHg	Dead weight tester

Parameter/Equipment	Range	CMC ² (±)	Comments
Mass	1 mg	0.60 µg	NISTIR 5672 SOP # 5 and SOP# 28 with OIML Class E1 weights
	2 mg	0.58 µg	
	3 mg	0.60 µg	
	5 mg	0.70 µg	
	10 mg	0.80 µg	
	20 mg	0.75 µg	
	30 mg	0.80 µg	
	50 mg	0.90 µg	
	0.10 g	1.1 µg	
	0.20 g	1.2 µg	
	0.30 g	1.2 µg	
	0.50 g	1.5 µg	
	1.0 g	2.2 µg	
	2.0 g	2.5 µg	
	3.0 g	3.4 µg	
	5.0 g	4.0 µg	
	10.0 g	6.3 µg	
	20.0 g	7.8 µg	
	30.0 g	11 µg	
	50.0 g	17 µg	
	100 g	29 µg	
	200 g	40 µg	
	300 g	60 µg	
	500 g	90 µg	
	1.0 kg	0.17 mg	
	2.0 kg	0.73 mg	
	3.0 kg	2.0 mg	
	5.0 kg	2.9 mg	
	10 kg	6.5 mg	
	20 kg	10 mg	
	25 kg	13 mg	
	1 oz	4.2×10^{-7} oz (0.012 mg)	
	2 oz	5.6×10^{-7} oz (0.016 mg)	
	4 oz	8.1×10^{-7} oz (0.023 mg)	
8 oz	3.9×10^{-6} oz (0.11 mg)		
1 lb	3.3×10^{-7} lb (0.15 mg)		
2 lb	4.4×10^{-7} lb (0.20 mg)		
3 lb	2.6×10^{-6} lb (1.2 mg)		
5 lb	4.6×10^{-6} lb (2.1 mg)		
10 lb	7.7×10^{-6} lb (3.5 mg)		
20 lb	2.9×10^{-5} lb (13 mg)		
30 lb	3.7×10^{-5} lb (17 mg)		
50 lb	4.9×10^{-5} lb (22 mg)		

VII. Thermodynamic

Parameter/Equipment	Range	CMC ² (±)	Comments
Relative Humidity	(10 to 90) % RH	1.0 % RH	Thunder Scientific 1200
Temperature – Measure and Measuring Equipment	0.01 °C	0.006 °C	Triple point of water cell
	(-40 to 0) °C	0.01 °C	SPRT and Hart Scientific super-thermometer
	(0 to 200) °C	0.01 °C	
	(200 to 300) °C	0.02 °C	
	(300 to 400) °C	0.03 °C	PRT and Hart Scientific super-thermometer
(400 to 600) °C	0.20 °C		
(600 to 800) °C	0.71 °C	S-Type thermocouple and precision TC display	

VIII. Time & Frequency

Parameter/Equipment	Range	CMC ² (±)	Comments
Frequency Dissemination	10 MHz	2.5 parts in 10 ¹¹ Hz/Hz	Fluke 910 GPS controlled frequency standard
Frequency – Measure	(0 to 500) MHz	3.6 µHz/Hz (+ 500 µHz for non- square/pulse signals)	HP 5345A/Fluke 910R GPS
	(0.4 to 1.6) GHz	5.8 µHz/Hz	HP 5345A/HP 5355A
	(1.5 to 18) GHz	6.3 µHz/Hz	HP 5345A/HP 5355A/HP 5356A
Stop Watches	(0.4 to 24) hr	0.02 s	Witschi New Tech Handy II watch calibrator

¹ This laboratory offers commercial dimensional testing/calibration service and field calibration service.

- ² Calibration and Measurement Capability Uncertainty (CMC) is the smallest uncertainty of measurement that a laboratory can achieve within its scope of accreditation when performing more or less routine calibrations of nearly ideal measurement standards or nearly ideal measuring equipment. CMCs represent expanded uncertainties expressed at approximately the 95 % level of confidence, usually using a coverage factor of $k = 2$. The actual measurement uncertainty of a specific calibration performed by the laboratory may be greater than the CMC due to the behavior of the customer's device and to influences from the circumstances of the specific calibration.
- ³ Field calibration service is available for this calibration and this laboratory meets A2LA R104 – *General Requirements: Accreditation of Field Testing and Field Calibration Laboratories* for these calibrations. Please note the actual measurement uncertainties achievable on a customer's site can normally be expected to be larger than the CMC found on the A2LA Scope. Allowance must be made for aspects such as the environment at the place of calibration and for other possible adverse effects such as those caused by transportation of the calibration equipment. The usual allowance for the actual uncertainty introduced by the item being calibrated, (e.g. resolution) must also be considered and this, on its own, could result in the actual measurement uncertainty achievable on a customer's site being larger than the CMC.
- ⁴ In the statement of CMC, L is the numerical value of the nominal length of the device measured in inches; D is the numerical value of the nominal diameter of the device measured in inches.
- ⁵ In the statement of CMC, % is the uncertainty percentage of the relative value of the reading, or the relative value of the reading plus floor specification, unless otherwise noted.
- ⁶ This laboratory meets R205 – *Specific Requirements: Calibration Laboratory Accreditation Program* for the types of dimensional calibrations listed above. Accredited test reports issued containing appropriate statements of measurement results, measurement uncertainty, and traceability are considered equivalent to a “calibration” certificate.



Accredited Laboratory

A2LA has accredited

CERTIFIED MEASUREMENTS, INC.

Centerville, GA

for technical competence in the field of

Calibration

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 *General requirements for the competence of testing and calibration laboratories*. This laboratory also meets any additional program requirements in the field of calibration. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated 8 January 2009).

Presented this 17th day of May 2016.



A handwritten signature in blue ink, reading "Jim C. Bunt".

Senior Director of Quality and Communications
For the Accreditation Council
Certificate Number 1297.01
Valid to May 31, 2018

For the calibrations to which this accreditation applies, please refer to the laboratory's Calibration Scope of Accreditation.